



**EXPEDITED PROCEDURE - EXAMINING GROUP 2822**

S/N 09/551,027

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Wendell P. Noble et al.

Examiner: Michael Trinh

Serial No.: 09/551,027

Group Art Unit: 2822

Filed: April 17, 2000

Docket: 303.379US2

Title: **CIRCUIT AND METHOD FOR A FOLDED BIT LINE MEMORY CELL WITH VERTICAL TRANSISTOR AND TRENCH CAPACITOR**

20/F Andolf  
9/4/02  
P. Weiler

**AMENDMENT & RESPONSE UNDER 37 C.F.R. § 1.116**

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Commissioner for Patents  
Washington, D.C. 20231

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TECHNOLOGY CENTER 2800

In response to the final Office Action mailed May 22, 2002, please amend the application as follows:

**IN THE CLAIMS**

Please substitute the claim set in the appendix entitled Clean Version of Pending Claims for the previously pending claim set. The substitute claim set is intended to reflect amendment of previously pending claims 20, 25, 41, 49, 51, 53 and 55. The specific amendments to individual claims are detailed in the following marked up set of claims.

20. (Amended) A method of fabricating a memory array, the method comprising the steps of:

forming from a single unbonded substrate a number of access transistors, each access transistor formed in a pillar of semiconductor material that extends outwardly from a substrate wherein each access transistor includes, in order, a first source/drain region, a body region and a second source/drain region formed vertically thereupon;

forming a trench capacitor in a trench [without forming an implanted barrier region in the substrate], wherein a first plate of the trench capacitor is integral with the first source/drain region of the access transistor;

forming a number of word lines in a number of trenches that separate adjacent rows of access transistors, wherein each trench includes two word lines with a gate of each word line interconnecting alternate access transistors on opposite sides of the trench;